

Defect oriented fault coverage of 100stuck-at fault test sets

Blyzniuk, M.; Cibakova, Tatiana; Gramatova, Elena; Kuzmicz, W.; Lobur, M.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** Proceedings of the 7th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2000 : Gdynia, Poland, 15-17 June 2000 2000 / p. 511-516 : ill <https://repo.pw.edu.pl/info/seam?ps=20&id=WUT7e20f35d67ae45d3b2d1264d7a4ba722&en&pn=1&cid=156607>

Defect-oriented library builder and hierarchical test generation

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Defect-oriented test generation using probabilistic estimation

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Hierarchical defect level test quality analysis

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Hierarchical defect-oriented fault simulation for digital circuits

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Hierarchical test generation for combinational circuits with real defects coverage

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Internet-based collaborative test generation with MOSCITO [Electronic resource]

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